

## Preface

The ISTFA conference proceedings are an integral part of technical libraries, failure analysis (FA) laboratories and related industries. In this 28<sup>th</sup> edition, you will find a comprehensive reference of the state-of-the-art research, development, tools and techniques presented at ISTFA 2002.

ISTFA is widely recognized within the worldwide FA community as a pacesetter, each year setting a new standard of excellence in furthering the science and technology of electronic device failure analysis. Once again this year, ISTFA proudly raises the level of knowledge and education on the newest FA innovations, including such topics as metrology and materials, optical probing, system level analysis, and FA process including high-speed analog and optoelectronics.

The predominant character of this year seems to be unpredictability – of economics, of politics, even of the next generation electronic mass products. Failure analysts are familiar with this situation: Unpredictability has always been one of the most challenging aspects of the FA business.

As the microelectronics industry continues to focus on economic recovery and revitalization, the FA community will have to be ready to

work on a large variety of products. More than ever, the key to successful failure analysis will be the wise selection and combination of an enormous range of techniques and tools. The Electronic Device Failure Analysis Society (EDFAS), through its ISTFA conference series and other educational offerings will continue taking an active role in leading this charge.

I would like to take this opportunity to thank everyone who contributed to ISTFA 2002 and encourage each of you to continue sharing your experiences and results in the development, manufacturing and assembly processes that are core to the ISTFA conferences and to the FA community worldwide.

“There is no success like failure”, I once heard Bob Dylan sing (and we would all join in). “And a failure is no success at all”, he continued. As failure analysts, we will succeed as long as we can find the failures... and we’ll be around for a while.

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